Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/712,923	IWASA ET AL.	VASA ET AL.	
Examiner	Art Unit	rt Unit	_
Toan Ton	2871	871	

	SEARCHED			
Class	Subclass	Date	Examiner	
349	113,110	3/15/2005	TTON	
	137			
<del>-</del>	44			
313	503			
		-		
_				
			-	
			·	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
			·

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST liquid crystal reflect\$ anti reflect\$ black mask/matrix light shield\$5/block\$ silicon ti tin al, mo, cr oxynitride,oxn	3/15/2005	TTON
		•
		,